

Search Notes**Application/Control No.**

10/766,725

Examiner

Chuck Huynh

Applicant(s)/Patent under Reexamination

CHOI ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	3/21/2007	CH
455	411	3/21/2007	CH
455	434	3/21/2007	CH
455	432.1	3/21/2007	CH
455	419	3/21/2007	CH
455	433	3/21/2007	CH
455	432	3/21/2007	CH
455	435.1	3/21/2007	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
455	434	3/21/2007	CH
PG Pub		3/21/2007	CH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	3/21/2007	CH
Combination Text search	3/21/2007	CH
Fwd/Bwd Citations	3/21/2007	CH
Talked to SPEs Ed Urban Duc Nguyen	3/21/2007	CH